

Dual N-Channel Advanced Power MOSFET

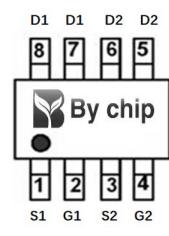
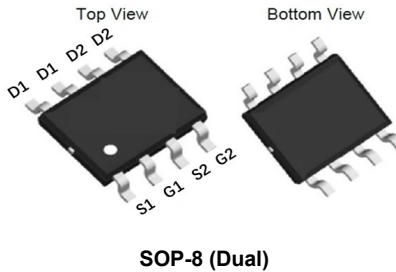
Features

- V_{DS} = 100V, I_D = 12 A
- RDS(ON) < 12 mΩ @ VGS = 10V
- RDS(ON) < 14 mΩ @ VGS = 4.5V

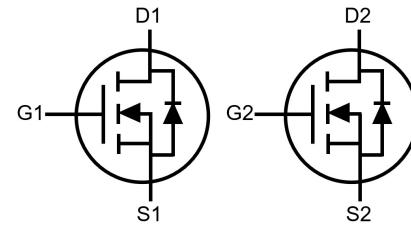
General Features

- Advanced Trench Technology
- Provide Excellent RDS(ON) and Low Gate Charge
- Lead Free and Green Available

100% UIS TESTED!
100% ΔVds TESTED!



Pin Assignment



Schematic diagram

ABSOLUTE MAXIMUM RATINGS (T_A = 25 °C, unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V _{DS}	100	V
Gate-Source Voltage	V _{GS}	± 20	
Continuous Drain Current (T _J = 150 °C)	T _C = 25 °C	12	A
	T _C = 70 °C	9.6	
	T _A = 25 °C	10 b, c	
	T _A = 70 °C	8.3 ^{b, c}	
Pulsed Drain Current (t = 300 μs)	I _{DM}	45	
Continuous Source-Drain Diode Current	T _C = 25 °C	5.4	
	T _A = 25 °C	2.7 ^{b, c}	
Single Pulse Avalanche Current	I _{AS}	30	
Avalanche Energy	E _{AS}	45	mJ
Maximum Power Dissipation	T _C = 25 °C	6	W
	T _C = 70 °C	3.8	
	T _A = 25 °C	3 ^{b, c}	
	T _A = 70 °C	1.9 ^{b, c}	
Operating Junction and Storage Temperature Range	T _J , T _{stg}	- 55 to 150	°C

THERMAL RESISTANCE RATINGS

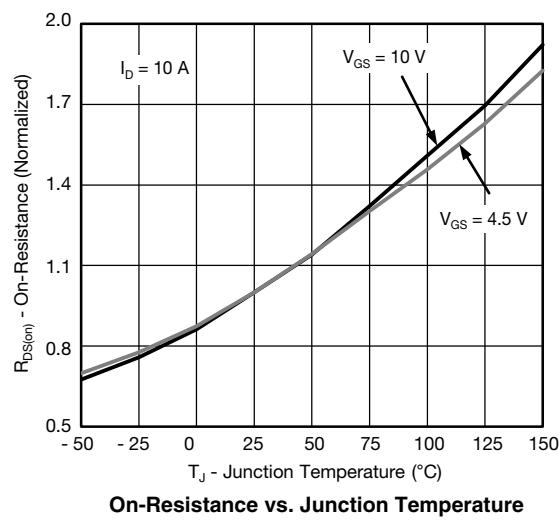
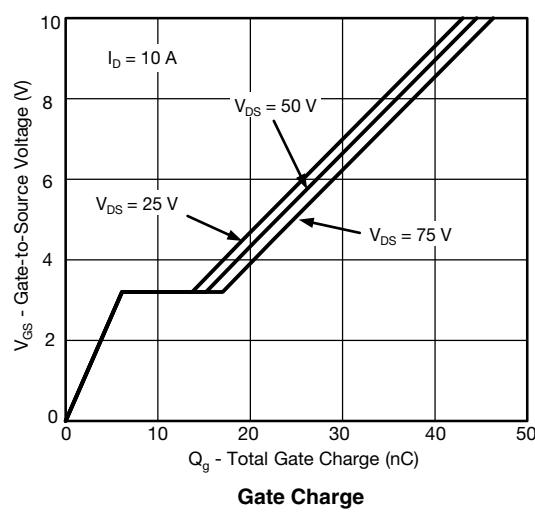
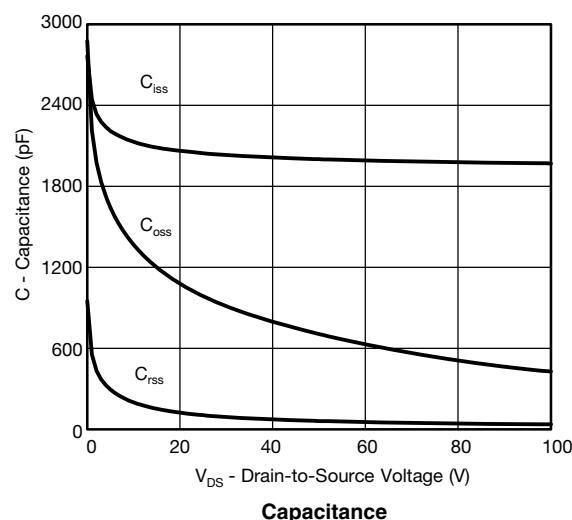
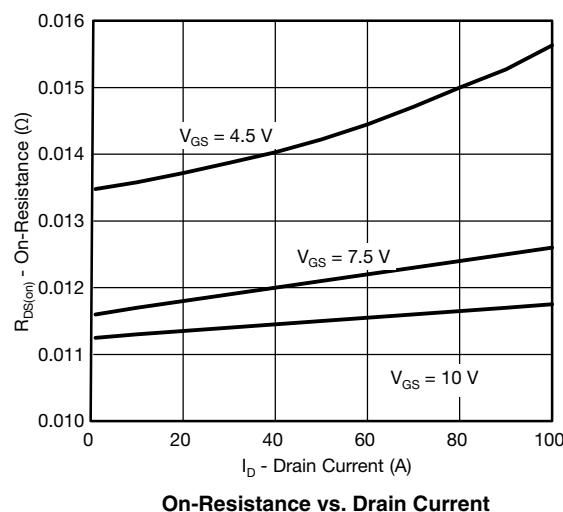
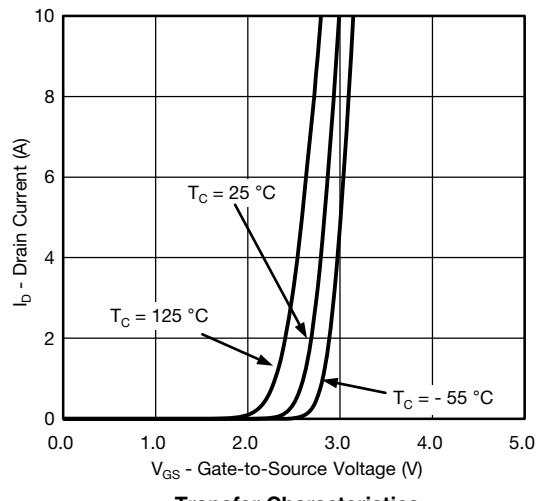
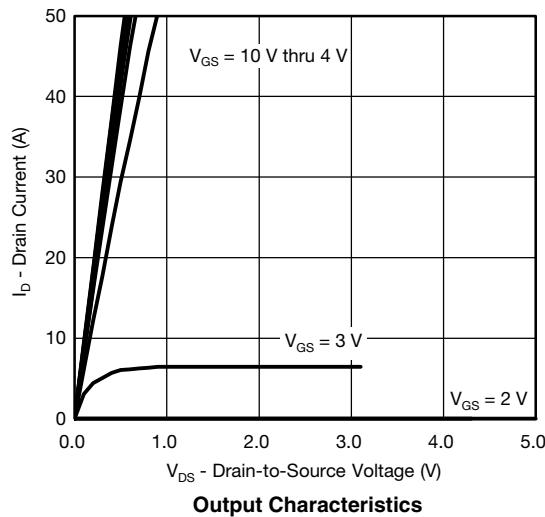
Parameter	Symbol	Typical	Maximum	Unit
Maximum Junction-to-Ambient ^{b, d}	R _{thJA}	33	42	°C/W
Maximum Junction-to-Foot (Drain)	R _{thJF}	16	21	

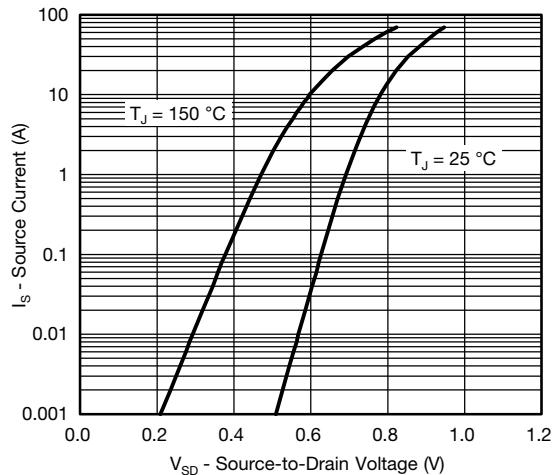
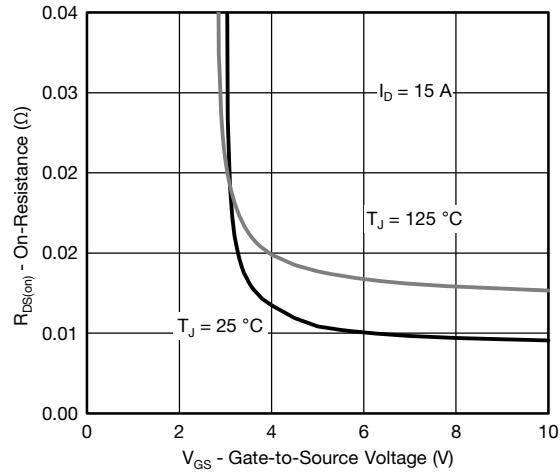
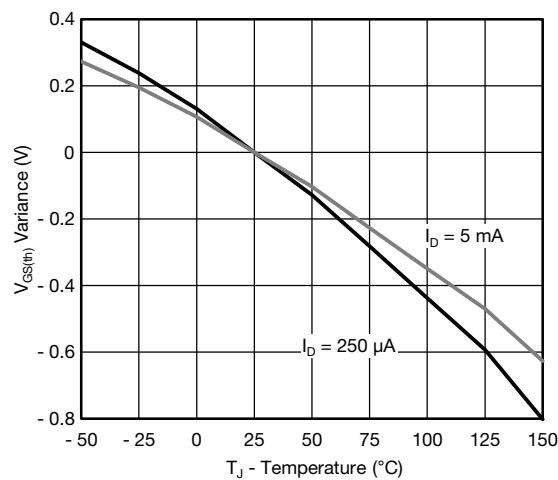
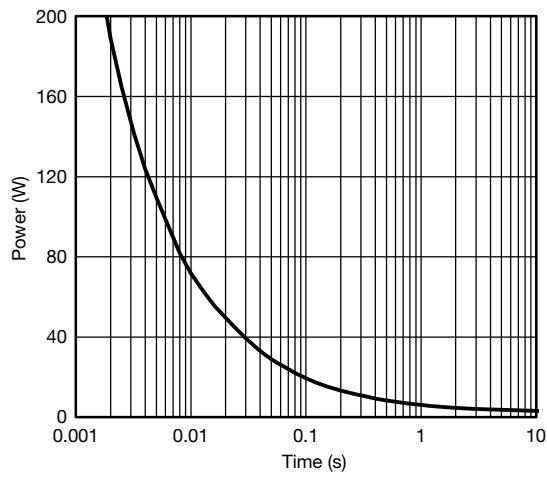
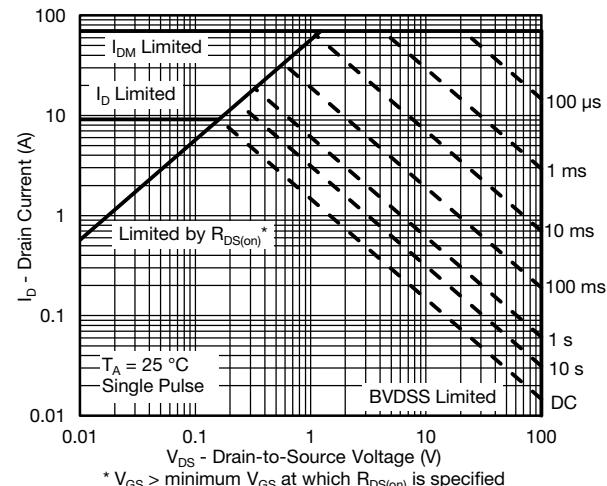
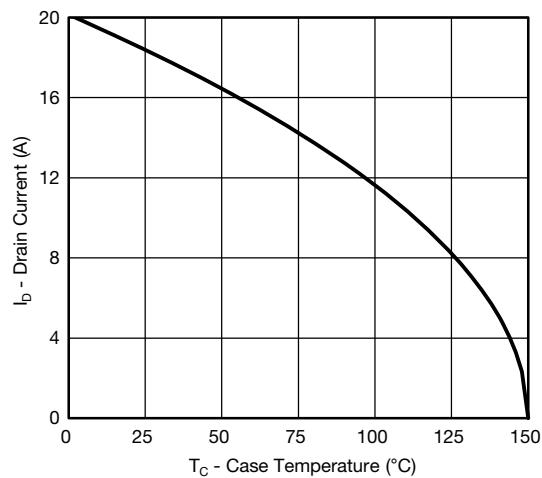
SPECIFICATIONS ($T_J = 25^\circ\text{C}$, unless otherwise noted)						
Parameter	Symbol	Test Conditions	Min.	Typ.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = 250 \mu\text{A}$	100			V
V_{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	$I_D = 250 \mu\text{A}$		64		mV/ $^\circ\text{C}$
$V_{GS(\text{th})}$ Temperature Coefficient	$\Delta V_{GS(\text{th})}/T_J$			- 5.8		
Gate-Source Threshold Voltage	$V_{GS(\text{th})}$	$V_{DS} = V_{GS}, I_D = 250 \mu\text{A}$	1.0		2.5	V
Gate-Source Leakage	I_{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zero Gate Voltage Drain Current	I_{DSS}	$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}$			1	μA
		$V_{DS} = 100 \text{ V}, V_{GS} = 0 \text{ V}, T_J = 55^\circ\text{C}$			10	
On-State Drain Current ^a	$I_{D(\text{on})}$	$V_{DS} \geq 5 \text{ V}, V_{GS} = 10 \text{ V}$	30			A
Drain-Source On-State Resistance ^a	$R_{DS(\text{on})}$	$V_{GS} = 10 \text{ V}, I_D = 10 \text{ A}$			0.012	Ω
		$V_{GS} = 7.5 \text{ V}, I_D = 10 \text{ A}$			0.013	
		$V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}$			0.014	
Forward Transconductance ^a	g_{fs}	$V_{DS} = 15 \text{ V}, I_D = 10 \text{ A}$		54		S
Dynamic^b						
Input Capacitance	C_{iss}	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		1970		pF
Output Capacitance	C_{oss}			695		
Reverse Transfer Capacitance	C_{rss}			62		
Total Gate Charge	Q_g	$V_{DS} = 50 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$		44.4	67	nC
Gate-Source Charge	Q_{gs}			20.7	31	
Gate-Drain Charge	Q_{gd}	$V_{DS} = 50 \text{ V}, V_{GS} = 4.5 \text{ V}, I_D = 8 \text{ A}$		6.1		
Output Charge	Q_{oss}			9.1		
Gate Resistance	R_g	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V}$		56	85	
Turn-On Delay Time	$t_{d(\text{on})}$	$f = 1 \text{ MHz}$	0.4	1.1	2.2	Ω
Rise Time	t_r	$V_{DD} = 50 \text{ V}, R_L = 5 \Omega$ $I_D \geq 10 \text{ A}, V_{GEN} = 7.5 \text{ V}, R_g = 1 \Omega$		15	30	ns
Turn-Off Delay Time	$t_{d(\text{off})}$			11	22	
Fall Time	t_f			31	60	
Turn-On Delay Time	$t_{d(\text{on})}$			10	20	
Rise Time	t_r	$V_{DD} = 50 \text{ V}, R_L = 5 \Omega$ $I_D \geq 10 \text{ A}, V_{GEN} = 10 \text{ V}, R_g = 1 \Omega$		12	24	
Turn-Off Delay Time	$t_{d(\text{off})}$			10	20	
Fall Time	t_f			34	65	
				10	20	
Drain-Source Body Diode Characteristics						
Continuous Source-Drain Diode Current	I_S	$T_C = 25^\circ\text{C}$			5.4	A
Pulse Diode Forward Current ^a	I_{SM}				70	
Body Diode Voltage	V_{SD}	$I_S = 5 \text{ A}$		0.76	1.1	V
Body Diode Reverse Recovery Time	t_{rr}	$I_F = 10 \text{ A}, di/dt = 100 \text{ A}/\mu\text{s}, T_J = 25^\circ\text{C}$		42	80	ns
Body Diode Reverse Recovery Charge	Q_{rr}			40	80	nC
Reverse Recovery Fall Time	t_a			19		ns
Reverse Recovery Rise Time	t_b			23		

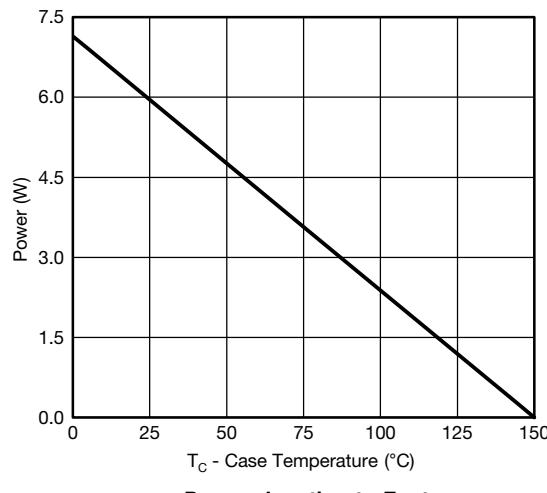
Notes:

- a. Pulse test; pulse width $\leq 300 \mu\text{s}$, duty cycle $\leq 2\%$
- b. Guaranteed by design, not subject to production testing.

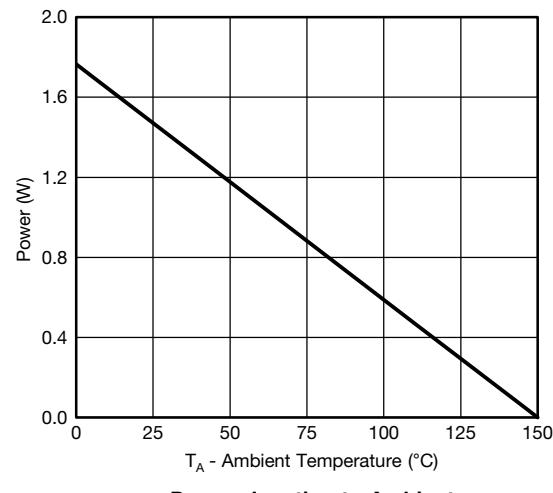
Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

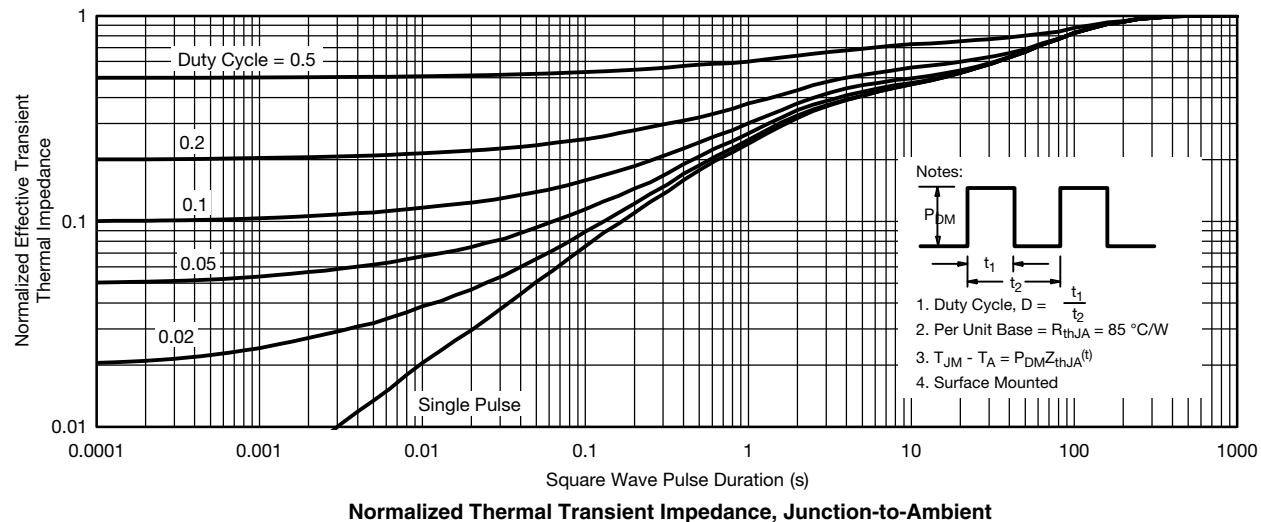
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)**Source-Drain Diode Forward Voltage****On-Resistance vs. Gate-to-Source Voltage****Threshold Voltage****Single Pulse Power, Junction-to-Ambient****Safe Operating Area, Junction-to-Ambient****Current Derating***

TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

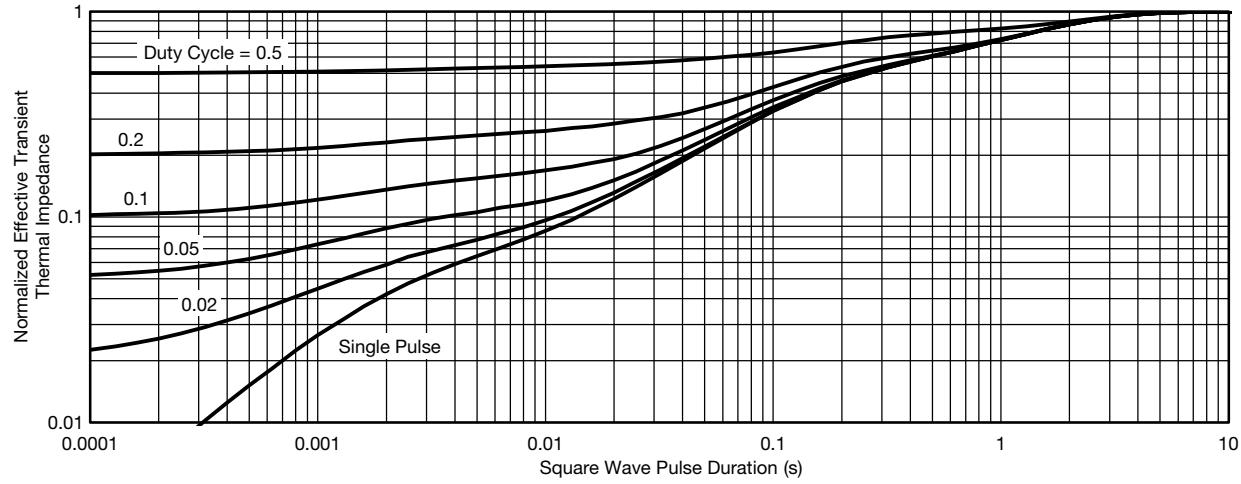
Power, Junction-to-Foot



Power, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Ambient



Normalized Thermal Transient Impedance, Junction-to-Foot